Crystal structure of 5-methoxy-2,3-dihydro-7*H*-dibenzo[*de*,*h*]quinolin-7-one, $C_{17}H_{13}NO_2$

E. Sobarzo-Sánchez*[I], B. K. Cassels[I], L. Castedo[II] and L. Valencia-Matarranz[III]

[I] Universidad de Chile, Facultad de Ciencias, Departamento de Química, Casilla 653 Santiago, Chile
[II] Universidad de Santiago de Compostela, Facultad de Química, Departamento de Química Orgánica y Unidad Asociada al C.S.I.C., ES-15706 Santiago de Compostela, Spain
[III] Universidad de Santiago de Compostela, Facultad de Química, Departamento de Química Inorgánica, ES-15782 Santiago de Compostela, Spain

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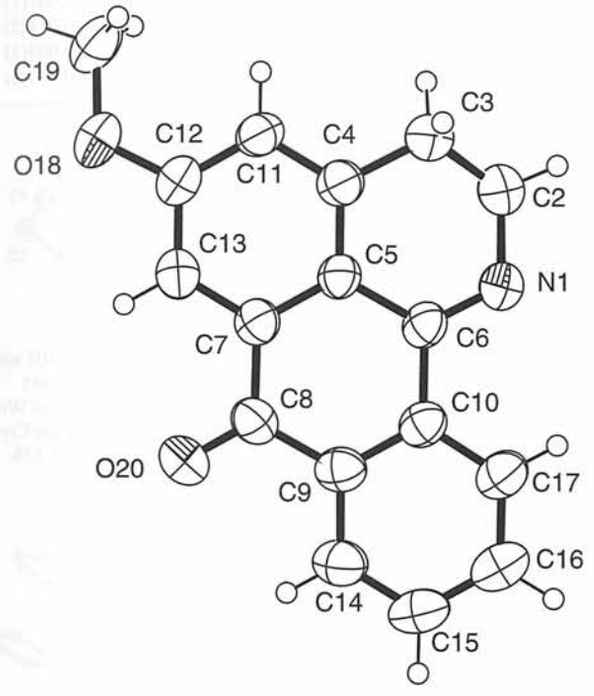

Abstract

$C_{17}H_{13}NO_2$, monoclinic, $P12_11$ (No. 4), $a = 5.0336(5)$ Å, $b = 13.964(2)$ Å, $c = 9.025(2)$ Å, $\beta = 98.56(1)°$, $V = 627.3$ Å^3, $Z = 2$, $R_{gt}(F) = 0.069$, $wR_{ref}(F^2) = 0.202$, $T = 293$ K.

Source of material

To a solution of phthalaldehydic acid (23 g, 153 mmol) in toluene (150 mL) was added homoveratrylamine (25 mL, 153 mmol) and the mixture was refluxed with stirring under a Dean-Stark trap for 2 hours at 413 K. The reaction mixture was then treated with polyphosphoric acid (80 g) and kept at 373 K for 10 minutes. The red mixture was dissolved in 100 mL water, neutralized with NH_3 and extracted with chloroform (700 ml). The chloroform extract was dried over anhydrous sodium sulphate, concenrated to dryness, and the residue subjected to flash chromatography on silica gel, eluting with hexane-ethyl acetate 95:5 (v/v) to give 5-methoxy-2,3-dihydro-7*H*-dibenzo[*de*,*h*]quinolin-7-one (12.00 g, yield 30%) recrystallized from MeOH as yellowish needles.

Discussion

The 5-methoxy-2,3-dihydro-oxoisoaporphine molecule is largely planar with two methylene carbons, C2 and C3, forming a torsion angle C6–N1–C2–C3 of 28.4(7)°. The methoxyl group carbon is coplanar with the aromatic ring with a C19–O18–C12 angle of 117.5(3)°.

Table 1. Data collection and handling.

Crystal:	yellow prism, size 0.16 × 0.24 × 0.64 mm
Wavelength:	Cu K_α radiation (1.54184 Å)
μ:	7.39 cm^{-1}
Diffractometer, scan mode:	Enraf Nonius Turbo CAD4, $\omega/2\theta$
$2\theta_{max}$:	144.06°
$N(hkl)_{measured}$, $N(hkl)_{unique}$:	4166, 2459
Criterion for I_{obs}, $N(hkl)_{gt}$:	$I_{obs} > 2\,\sigma(I_{obs})$, 2140
$N(param)_{refined}$:	184
Programs:	SIR-97 [1], SHELXL-97 [2], ORTEP-3 [3], WinGX [4]

Table 2. Atomic coordinates and displacement parameters (in Å^2).

Atom	Site	x	y	z	U_{iso}
H(2A)	2*a*	0.1306	1.0774	0.5773	0.126
H(2B)	2*a*	0.0105	1.0801	0.7269	0.126
H(3A)	2*a*	0.4298	1.0848	0.8019	0.085
H(3B)	2*a*	0.4972	1.0139	0.6783	0.085
H(11)	2*a*	0.7186	0.9898	0.9989	0.063
H(13)	2*a*	0.4364	0.7343	1.1084	0.067
H(14)	2*a*	–0.3627	0.5934	0.7942	0.075
H(15)	2*a*	–0.6772	0.5968	0.5803	0.083
H(16)	2*a*	–0.6986	0.7278	0.4215	0.083
H(17)	2*a*	–0.4020	0.8522	0.4717	0.073
H(19A)	2*a*	0.8881	0.9841	1.2461	0.110
H(19B)	2*a*	1.0923	0.9341	1.1558	0.110
H(19C)	2*a*	1.0992	0.9114	1.3265	0.110

* Correspondence author (e-mail: esobarzo@usc.es)

Table 3. Atomic coordinates and displacement parameters (in Å^2).

Atom	Site	x	y	z	U_{11}	U_{22}	U_{33}	U_{12}	U_{13}	U_{23}
N(1)	2*a*	–0.0519(5)	0.9572(2)	0.6187(3)	0.064(2)	0.062(2)	0.073(2)	–0.008(1)	–0.016(1)	0.017(1)
C(2)	2*a*	0.111(1)	1.0407(3)	0.6662(6)	0.103(3)	0.079(2)	0.114(3)	–0.029(2)	–0.044(3)	0.043(2)
C(3)	2*a*	0.3728(7)	1.0263(2)	0.7484(4)	0.071(2)	0.057(2)	0.078(2)	–0.013(1)	–0.013(2)	0.012(1)
C(4)	2*a*	0.3891(5)	0.9461(2)	0.8576(3)	0.048(1)	0.046(1)	0.057(2)	0.004(1)	0.004(1)	–0.003(1)
C(5)	2*a*	0.2018(5)	0.8729(2)	0.8292(3)	0.040(1)	0.044(1)	0.052(1)	0.0045(9)	0.0022(9)	0.001(1)
C(6)	2*a*	–0.0105(5)	0.8812(2)	0.7002(3)	0.041(1)	0.049(1)	0.051(1)	0.006(1)	0.002(1)	–0.002(1)
C(7)	2*a*	0.2198(5)	0.7929(2)	0.9248(3)	0.046(1)	0.046(1)	0.052(1)	0.005(1)	0.007(1)	–0.002(1)
C(8)	2*a*	0.0242(6)	0.7132(2)	0.8956(4)	0.059(2)	0.044(1)	0.065(2)	0.001(1)	0.005(1)	0.004(1)
C(9)	2*a*	–0.1827(6)	0.7202(2)	0.7611(4)	0.049(1)	0.047(1)	0.064(2)	0.001(1)	0.009(1)	–0.008(1)
C(10)	2*a*	–0.1969(5)	0.7995(2)	0.6643(3)	0.043(1)	0.052(1)	0.053(1)	0.003(1)	0.005(1)	–0.006(1)
C(11)	2*a*	0.5935(5)	0.9406(2)	0.9802(3)	0.047(1)	0.054(1)	0.054(1)	–0.006(1)	–0.000(1)	–0.005(1)
C(12)	2*a*	0.6092(5)	0.8612(2)	1.0744(3)	0.047(1)	0.061(2)	0.049(1)	0.004(1)	–0.001(1)	–0.002(1)
C(13)	2*a*	0.4238(6)	0.7875(2)	1.0459(3)	0.059(2)	0.054(2)	0.053(2)	0.003(1)	0.002(1)	0.006(1)
C(14)	2*a*	–0.3680(6)	0.6452(2)	0.7291(4)	0.056(1)	0.055(2)	0.077(2)	–0.007(1)	0.010(1)	–0.003(2)
C(15)	2*a*	–0.5578(6)	0.6475(3)	0.6019(4)	0.056(2)	0.067(2)	0.082(2)	–0.015(2)	0.004(1)	–0.017(2)
C(16)	2*a*	–0.5694(6)	0.7258(3)	0.5066(4)	0.055(2)	0.079(2)	0.069(2)	–0.009(2)	–0.001(1)	–0.015(2)
C(17)	2*a*	–0.3921(6)	0.8003(2)	0.5369(4)	0.052(1)	0.065(2)	0.062(2)	–0.002(1)	–0.001(1)	–0.007(1)
C(19)	2*a*	0.9848(7)	0.9260(3)	1.2344(4)	0.065(2)	0.085(2)	0.062(2)	0.003(2)	–0.015(1)	–0.014(2)
O(18)	2*a*	0.7992(5)	0.8496(2)	1.1968(2)	0.067(1)	0.082(2)	0.056(1)	–0.002(1)	–0.0147(9)	0.003(1)
O(20)	2*a*	0.0367(5)	0.6439(2)	0.9785(3)	0.085(2)	0.055(1)	0.084(2)	–0.012(1)	–0.005(1)	0.017(1)

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